

## SEARCHED

Class	Sub.	Date	Exmr.
455	450	6/26/04	R.V.G.
	451	6/26/04	R.V.G.
	452.1	6/26/04	R.V.G.
	452.2	6/26/04	R.V.G.
	453	6/26/04	R.V.G.
370	328	6/26/04	R.V.G.
	329	6/26/04	R.V.G.
	330	6/26/04	R.V.G.
	331	6/26/04	R.V.G.
	332	6/26/04	R.V.G.
	333	6/26/04	R.V.G.
	334	6/26/04	R.V.G.
	335	6/26/04	R.V.G.
	336	6/26/04	R.V.G.
	337	6/26/04	R.V.G.

## INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

EAST Image and keyword search in USPAT, USFPAUS, EPO, IBM-TDB, JPO and DERWENT	Date	Exmr.
Inventor names and Assignee search in PALAT EXPO and EAST	6/26/04	R.V.G.
WIPO Database <a href="http://patgazette.wipo.int/">http://patgazette.wipo.int/</a>	6/26/04	R.V.G.
EPO Database <a href="http://ep.espacenet.com">http://ep.espacenet.com</a>	6/26/04	R.V.G.
IEEE Xplore <a href="http://ieeexplore.ieee.org/Xplore/login.jsp">http://ieeexplore.ieee.org/Xplore/login.jsp</a>	6/26/04	R.V.G.
Lee Nguyen 455	6/26/04	R.V.G.

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